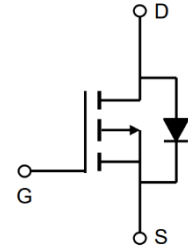


-60V P-Channel Enhancement Mode MOSFET

Description

The AP80P06D uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 6V. This device is suitable for use as a Battery protection or in other Switching application.



General Features

$V_{DS} = -60V$ $I_D = -80A$

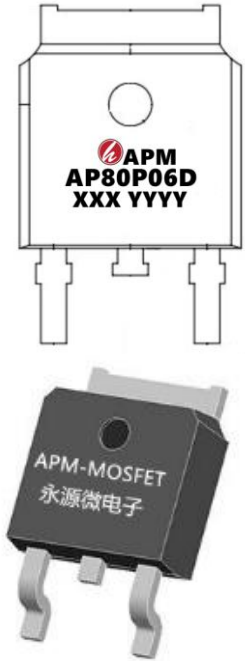
$R_{DS(ON)} < 11m\Omega$ @ $V_{GS} = -10V$ (Type: $9m\Omega$)

Application

Lithium battery protection

Wireless impact

Mobile phone fast charging



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP80P06D	TO-252-3L	AP80P06D XXX YYYY	2500

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-60	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-80	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $-V_{GS} @ -10V^1$	-50	A
I_{DM}	Pulsed Drain Current ²	-320	A
EAS	Single Pulse Avalanche Energy ³	450	mJ
I_{AS}	Avalanche Current	41	A
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	110	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	1.1	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	60	$^\circ C/W$

-60V P-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_C=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =-250μA	-60	-68	---	V
ΔBVDSS/ΔT _J	BV _{DSS} Temperature Coefficient	Reference to 25°C, I _D =-1mA	---	-0.035	---	V/°C
RDS(ON)	Static Drain-Source On-Resistance ²	V _{GS} =-10V, I _D =-20A	---	9.0	11	mΩ
		V _{GS} =-4.5V, I _D =-15A	---	12	16	
VGS(th)	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =-250μA	-1.0	-1.8	-2.5	V
ΔVGS(th)	VGS(th) Temperature Coefficient		---	4.28	---	mV/°C
IDSS	Drain-Source Leakage Current	V _{DS} =-60V, V _{GS} =0V, T _J =25°C	---	---	1	μA
		V _{DS} =-60V, V _{GS} =0V, T _J =55°C	---	---	5	
IGSS	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA
gfs	Forward Transconductance	V _{DS} =-5V, I _D =-20A	---	50	---	S
R _g	Gate Resistance	V _{DS} =0V, V _{GS} =0V, f=1MHz	---	2.0	---	Ω
Q _g	Total Gate Charge (-4.5V)	V _{DS} =-30V, V _{GS} =-10V, I _D =-20A	---	56	---	nC
Q _{gs}	Gate-Source Charge		---	11	---	
Q _{gd}	Gate-Drain Charge		---	9	---	
Td(on)	Turn-On Delay Time	V _{DD} =-30V, V _{GS} =-10V, R _G =3Ω, I _D =-20A	---	4.5	---	ns
T _r	Rise Time		---	2.5	---	
Td(off)	Turn-Off Delay Time		---	14.5	---	
T _f	Fall Time		---	3.8	---	
C _{iss}	Input Capacitance	V _{DS} =-15V, V _{GS} =0V, f=1MHz	---	3500	---	pF
C _{oss}	Output Capacitance		---	600	---	
Cr _{ss}	Reverse Transfer Capacitance		---	25	---	
I _s	Continuous Source Current ^{1,5}	V _G =V _D =0V, Force Current	---	---	-80	A
ISM	Pulsed Source Current ^{2,5}		---	---	-240	A
VSD	Diode Forward Voltage ²	V _{GS} =0V, I _S =-1A, T _J =25°C	---	---	-1.2	V

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%
- 3、The EAS data shows Max. rating. The test condition is V_{DD}=-48V, V_{GS}=-10V, L=0.1mH, I_{AS}=-41A
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.

Typical Characteristics

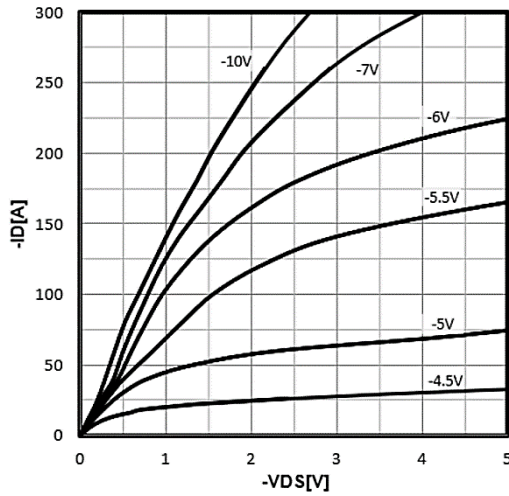


Figure 1. Type. Output Characteristics ($T_j=25\text{ }^\circ\text{C}$)

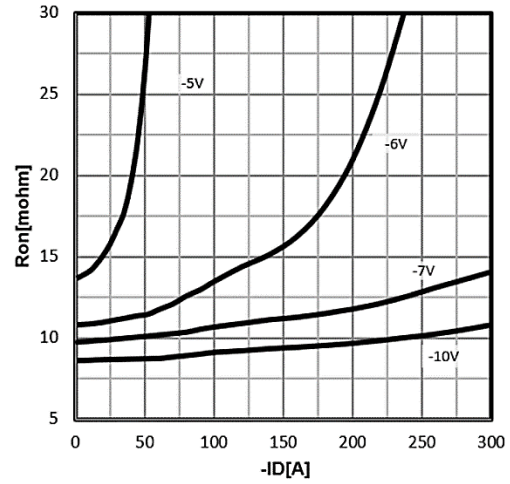


Figure 2. Type. drain-source on resistance

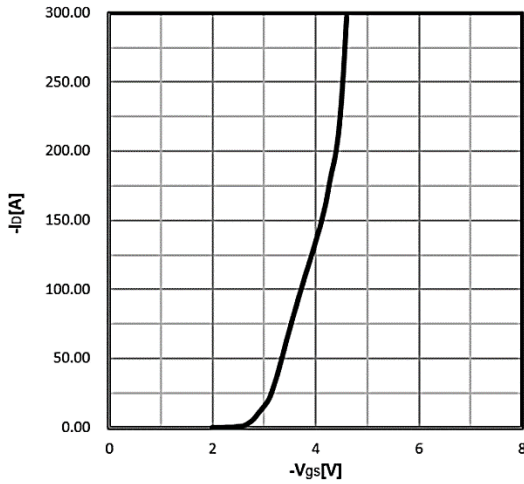


Figure 3. Type. transfer characteristics

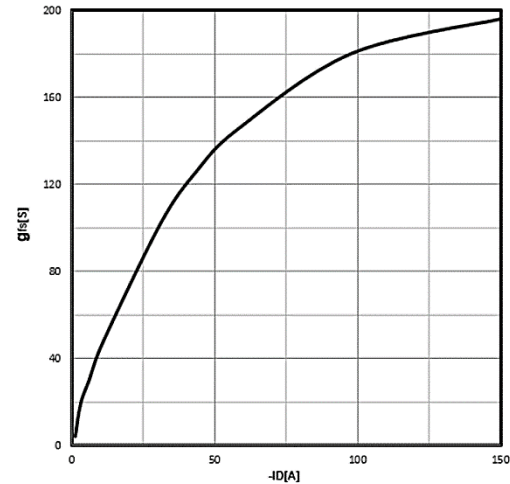


Figure 4. Type. forward transconductance

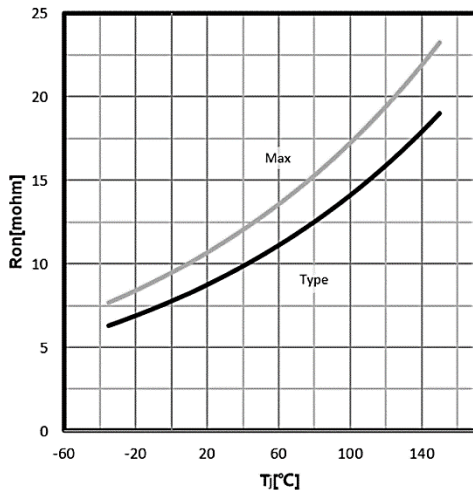


Figure 5. Drain-source on-state resistance $R_{DS(on)} = f(T_j)$; $I_D = 80\text{A}$; $V_{GS} = 10\text{V}$

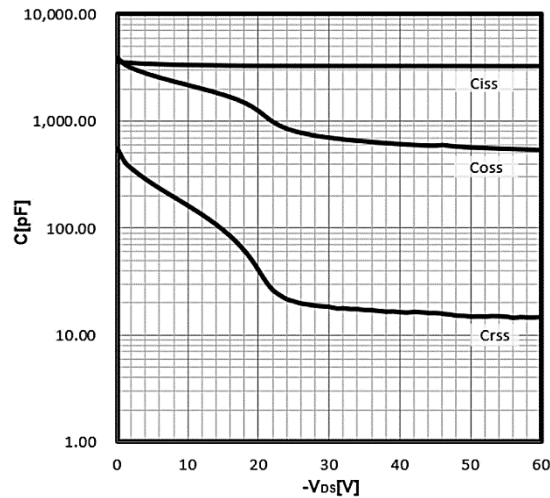


Figure 6. Body-Diode Characteristics $C = f(V_{DS})$; $V_{GS} = 0\text{V}$; $f = 1\text{MHz}$



-60V P-Channel Enhancement Mode MOSFET

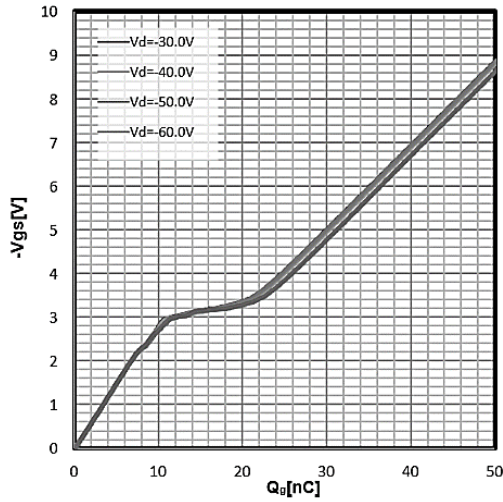


Figure 7. Typ. gate charge
 $V_{GS} = f(Q_{gate})$; $I_D = 20A$

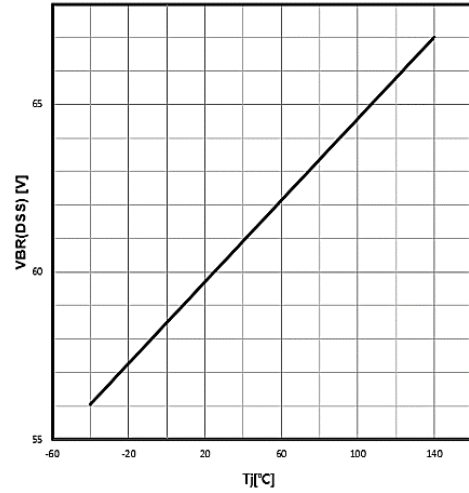


Figure 8. Drain Current Derating
 $V_{BR(DSS)} = f(T_j)$; $I_D = 250\mu A$

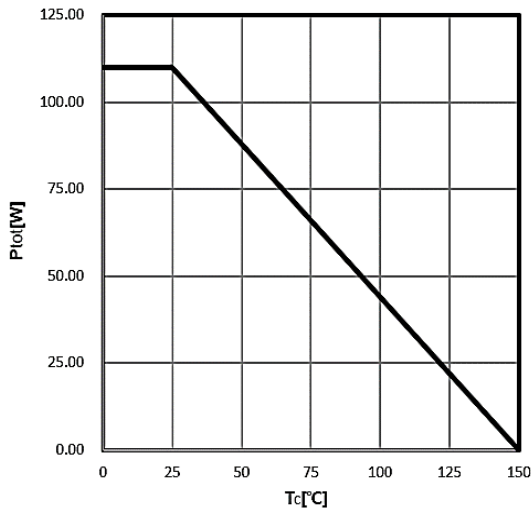


Figure 7. Power Dissipation

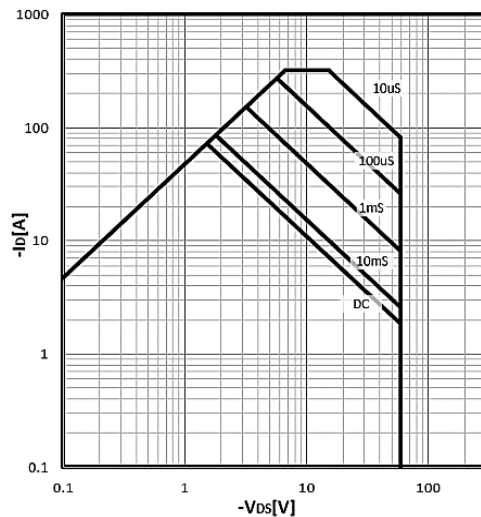


Figure 8. Safe operating area

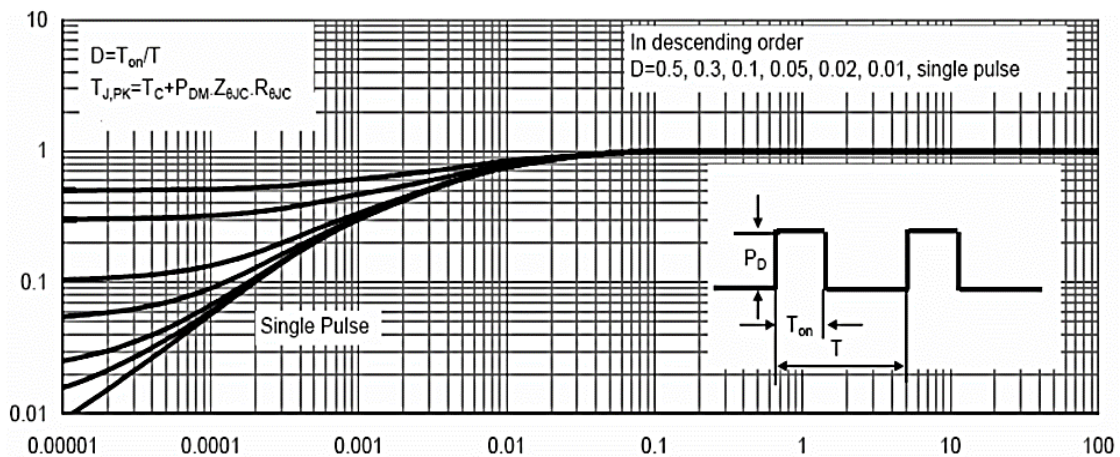
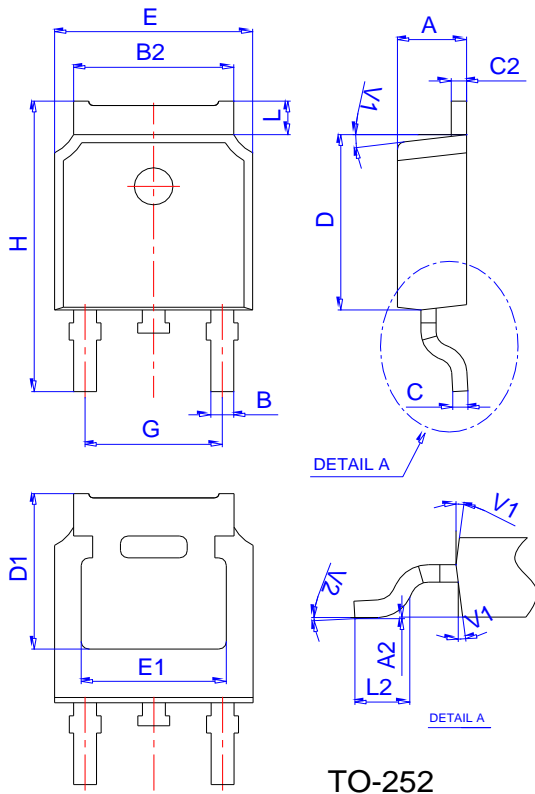


Figure 10. Max. transient thermal impedance

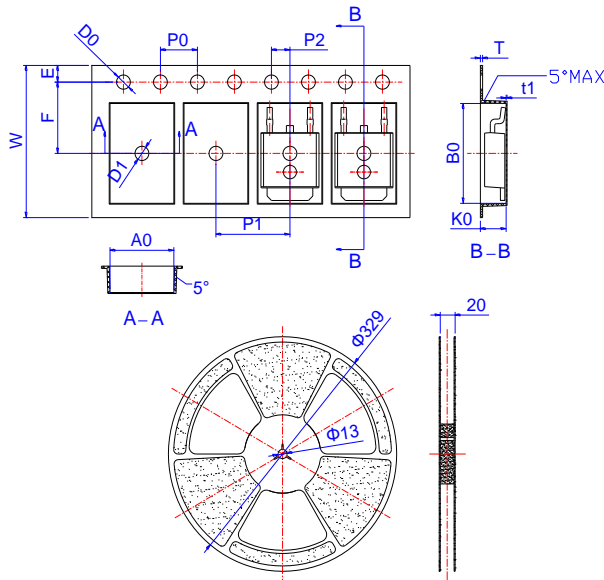
$Z_{thJC} = f(t_p)$

Package Mechanical Data: TO-252-3L



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

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Edition	Date	Change
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